

<b>Notice of References Cited</b>	Application/Control No. 10/565,709		Applicant(s)/Patent Under Reexamination ABEDI, SAIED	
	Examiner Meless N. Zewdu		Art Unit 2617	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0080719 A1	06-2002	Parkvall et al.	370/235
*	B	US-2003/0169709 A1	09-2003	Oki, Noboru	370/335
*	C	US-2003/0166408 A1	09-2003	Zhang et al.	455/522
*	D	US-2003/0103514 A1	06-2003	Nam et al.	370/412
*	E	US-2002/0094778 A1	07-2002	Cannon et al.	455/41
*	F	US-2004/0196804 A1	10-2004	Love et al.	370/329
*	G	US-2003/0185155 A1	10-2003	Huang et al.	370/235
*	H	US-7,403,892 B2	07-2008	Sjoberg et al.	704/201
*	I	US-6,047,000	04-2000	Tsang et al.	370/412
*	J	US-6,728,208 B1	04-2004	Puuskari, Mikko	370/230.1
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.